

WE CLAIM:

1. a replica Gm cell comprising:
 - at least one Gm setting device;
 - a pair of input transistors connected with said Gm setting device,
- 5 each input transistor operable to receive a reference voltage;
 - an error amplifier connected with said pair of input transistors;
 - a reference current source connected with said error amplifier; and
 - a current mirror connected with said error amplifier.
2. The replica Gm cell of Claim 1 wherein said at least one Gm setting
- 10 device comprises a pair of transistors, said transistors having gates that are tied together.
3. The replica Gm cell of Claim 1 wherein said at least one Gm setting device comprises a plurality of transistors, said transistors having sources that are tied together and drains that are tied together.
- 15 4. The replica Gm cell of Claim 1 wherein said at least one Gm setting device is arranged in a binary coded configuration.
5. The replica Gm cell of Claim 1 wherein said at least one Gm setting device is arranged in a thermometer coding configuration.
6. The replica Gm cell of Claim 1 wherein said at least one Gm setting
- 20 device is arranged in a segmented thermometer coding configuration.
7. The replica Gm cell of Claim 1 wherein each of said input transistors are operable to receive a reference voltage.
- 25 8. The replica Gm cell of Claim 1 wherein said reference current source comprises a current multiplying digital-to-analog converter.
9. The replica Gm cell of Claim 1 wherein said reference current source comprises a current multiplying digital to analog converter and a current mirror.
10. 10. The replica Gm cell of Claim 1 further comprising a tail current source connected with said reference current source.
- 30 11. The replica Gm cell of Claim 1 wherein said current mirror comprises:

- a mirror reference transistor, said mirror reference transistor having a gate, source, and drain connected with a first input of said error amplifier; and
- 5 a mirrored pull-up current source, said mirrored pull-up current source having a gate connected with said gate of said mirror reference transistor and said first input of said error amplifier, a source connected with said source of said mirror reference transistor, and a drain connected with a second input of said error amplifier.
- 10 *13.12* The replica Gm cell of Claim 1 wherein said current mirror comprises:
- a mirror reference transistor, said mirror reference transistor having a gate, a source, and a drain;
- 15 a first cascode transistor, said first cascode transistor having a gate, a source connected with the drain of said mirror reference transistor, and a drain connected with a first input of said error amplifier;
- a mirrored pull-up current source, said mirrored pull-up current source having a gate connected with said gate of said mirror reference transistor and said first input of said error amplifier, a source connected with said source of said mirror reference transistor, and a drain;
- 20 a second cascode transistor, said second cascode transistor having a gate connected with said gate of said first cascode transistor, a source connected with the drain of said mirrored pull-up current source, and a drain connected with a second input of said error amplifier.
- 25 *14.13* a replica Gm cell comprising:
- a digital to analog converter, said digital to analog converter operable to receive a Gm setting code and output a current having a magnitude proportional to said Gm setting code;
- 30 a current mirror connected with said digital-to-analog converter; a mirror reference transistor connected with said current mirror;

a mirrored pull-up current source connected with said current mirror and said mirror reference transistor;

a tail current source connected with said digital to analog converter; at least one Gm setting device connected with said tail current

5 source;

a first input transistor connected with said at least one Gm setting device;

a second input transistor connected with said at least one Gm setting device; and

10 an error amplifier operable to provide a tuning voltage to said Gm setting device, said error amplifier having a first input and a second input,

wherein said error amplifier generates said tuning voltage by comparing a first voltage located between said first input transistor and said mirrored pull-up current source with a second voltage located between said second input transistor and said mirror reference transistor.

15

~~15.~~ ¹⁴ The replica Gm cell of Claim ~~14~~ ¹³ further comprising a first cascode transistor connected with said mirrored pull-up current source and said first input of said error amplifier and second cascode transistor connected with said mirror reference transistor and said second input of said error amplifier.

20 ~~16.~~ ¹⁵ The replica Gm cell of Claim ~~14~~ ¹³ further comprising a first cascode transistor connected with said first input transistor and said error amplifier and a second cascode transistor connected with said second input transistor and said error amplifier.

~~17.~~ ¹⁶ The replica Gm cell of Claim ~~14~~ ¹³ wherein said at least one Gm setting device comprises a plurality of Gm setting devices, each of said Gm setting devices comprising at least one transistor with a source, gate, and drain and said plurality of Gm setting devices having said sources tied together and said drains tied together.

18. ¹⁷ The replica Gm cell of Claim ~~17~~ further comprising a switching circuit connected with said plurality of Gm setting devices and operable to receive said Gm setting code and provide a voltage to said gates of said Gm setting devices.

5 19. ¹⁸ The replica Gm cell of Claim ~~17~~ wherein said digital to analog converter is operable to receive a Gm setting code having a number of bits greater than a number of Gm setting devices.

10 20. ¹⁹ A method for calibrating a Gm cell comprising the acts of:
providing a Gm cell;
providing a replica Gm cell connected with said Gm cell;
providing a high reference voltage and a low reference voltage to said Gm cell;
providing a Gm setting code to said Gm replica cell;
generating a tuning voltage utilizing said replica Gm cell;
15 adjusting said tuning voltage until the difference between a pair of drain currents that flow through a pair of input transistors is substantially equal to a reference current;
utilizing the tuning voltage generated by said replica Gm cell in said Gm cell.

20 21. ²⁰ The method of claim ~~20~~, further comprising the act of providing said Gm setting code to said Gm cell.

22. ²¹ The method of claim ~~20~~, further comprising the act of generating a bias voltage to said Gm cell utilizing to said Gm replica cell.

25 23. ²² A digitally programmable generalized biquad comprising:
a first Gm cell operable to receive a differential voltage input and a tuning voltage and generate a differential voltage output;
a second Gm cell operable to receive a differential voltage input and a tuning voltage and generate a differential voltage output;

- a first replica Gm cell operable to receive a high reference voltage, a low reference voltage, and a Gm setting code and generate a tuning voltage, said first replica Gm cell connected with said first Gm cell;
- 5 a second replica Gm cell operable to receive a high reference voltage, a low reference voltage, and a Gm setting code and generate a tuning voltage, said second replica Gm cell connected with said second Gm cell;
- a first common mode feedback circuit connected with said first Gm cell; and
- 10 a second common mode feedback circuit connected with said second Gm cell.

23 24. The digitally programmable generalized biquad of claim *23* wherein said first Gm cell and said second Gm cell are operable to receive said Gm setting code.

25 25. The digitally programmable generalized biquad of claim *23* wherein said first replica Gm cell is operable to generate a bias voltage and said first Gm cell is operable to receive said bias voltage.

26 26. The digitally programmable generalized biquad of claim *23* wherein said second replica Gm cell is operable to generate a bias voltage and said second Gm cell is operable to receive said bias voltage.

20 27. The digitally programmable generalized biquad of claim *23* further comprising at least one additional first Gm cell connected with said first Gm replica cell.